Layout-Based 3D Solid Modeling of IC Structures and Interconnects Including Electrical Parameter Extraction

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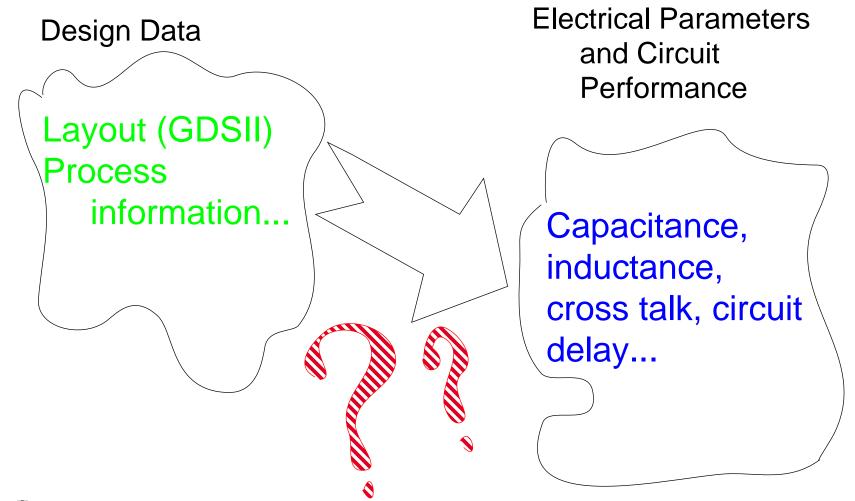


Outline

- Background and Motivation
- System Configuration
- Layout-Based 3D Solid Modeling
- Level-Set Method for Surface Meshing of Complex Geometry
- Capacitance Extraction for a Four-Transistor SRAM Cell
- Summary and Discussion



Background and Motivation



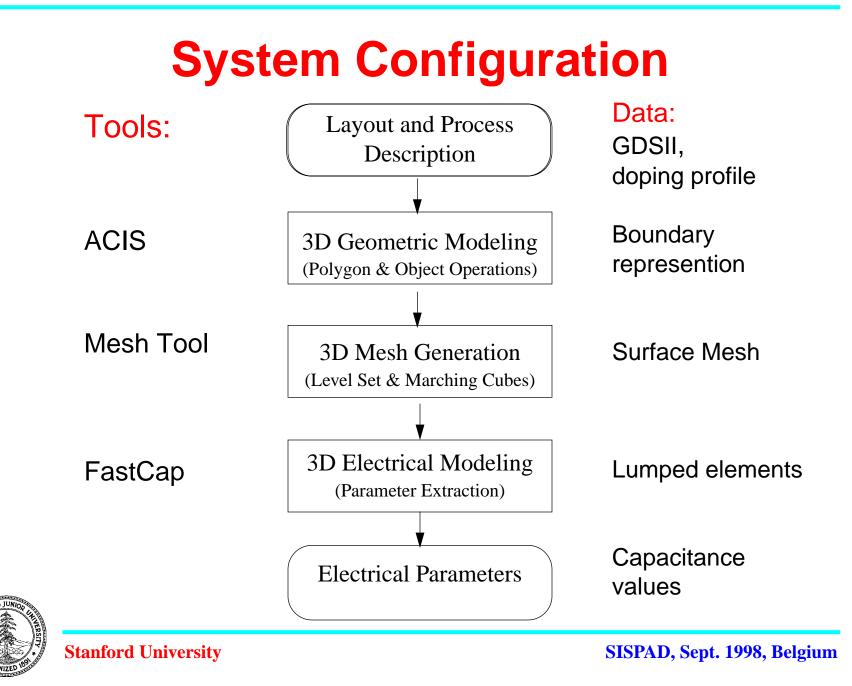


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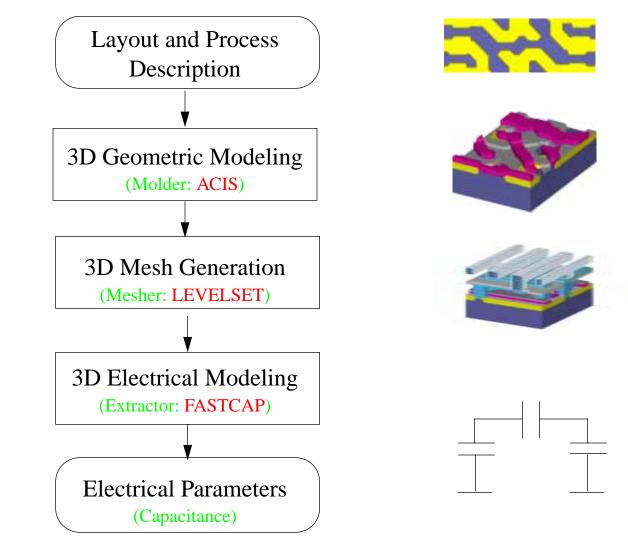
Background and Motivation

- Timely technology development requires the prediction of circuit performance based directly on the design data.
- Need to link directly the impact of layout and processing on the electrical characteristics of complex IC structures and interconnects.
- Current commercial tools are still evolving to provide abilities of modeling IC structures with complex 3D geometry.





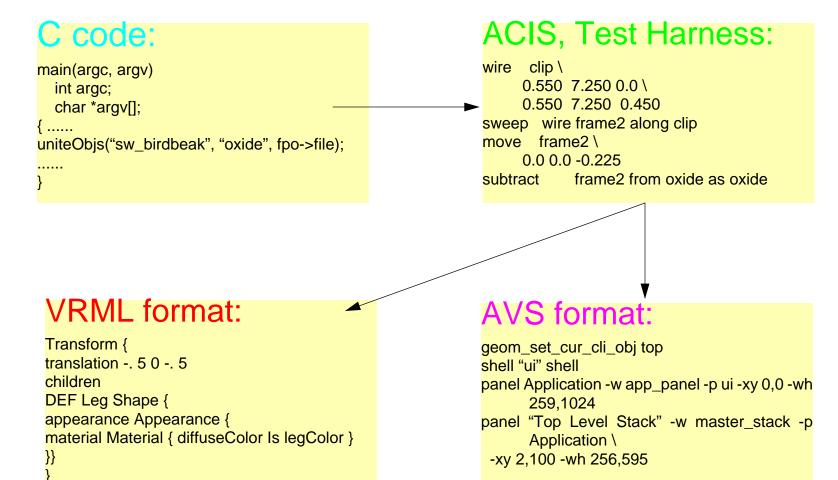
System Configuration





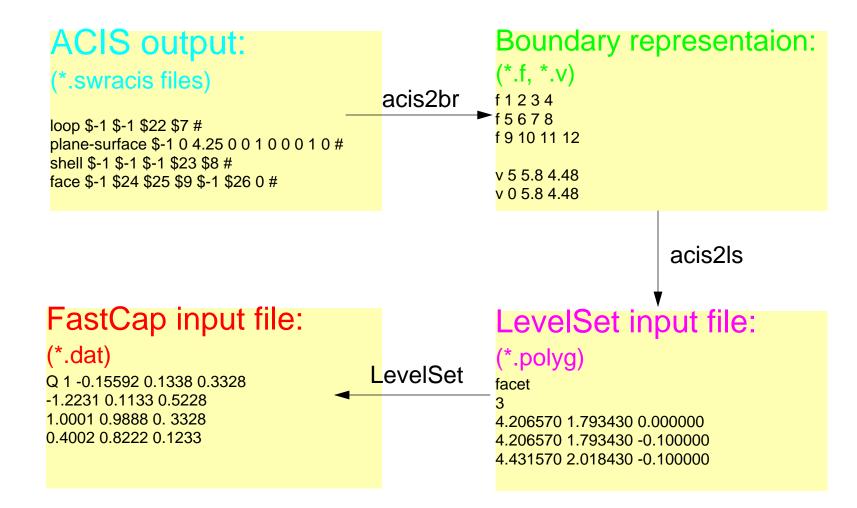
- Generating input files for the geometry modeler to specify the structure of each component in a 3D object
- Running the geometry modeler to obtain description files for the geometry
- Converting the output files from the geometry modeler to geometry files readable to 3D visualization program
- Displaying and manipulating 3D image using the visualization program



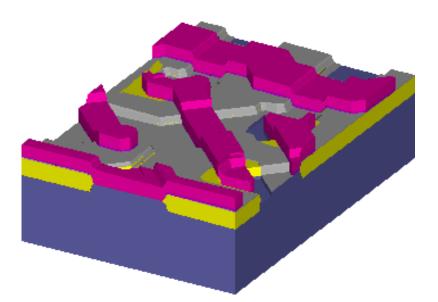




Solid Modeling to Elec. Extraction

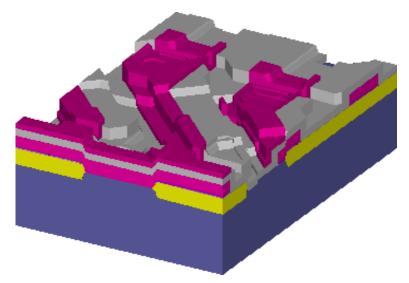






Solid geometry after the first poly layer is formed.

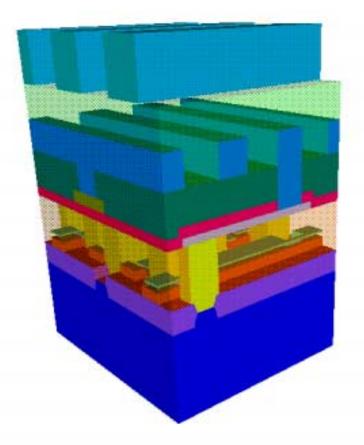
Solid geometry after the second poly layer is formed.





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- SRAM in VRML format displayed by VRML browser across Internet with two insulating layers transparent



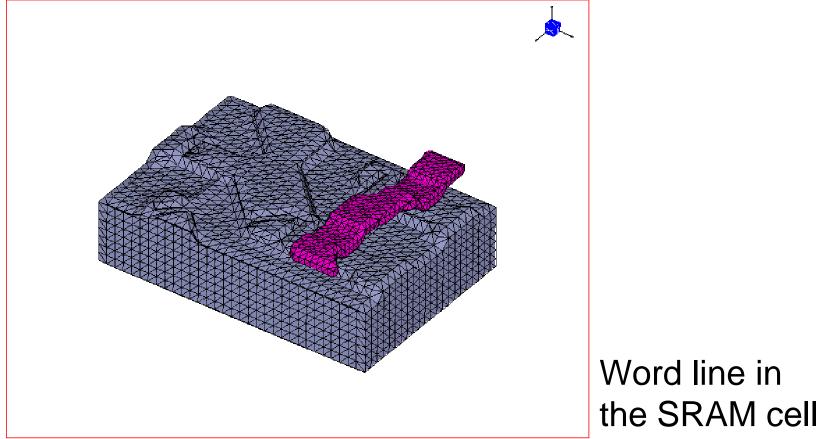


Level-Set Method for Surface Meshing of Complex Geometry

- Surface polygons from the solid modeler are triangulated into a coarse mesh.
- Octants containing the geometric object are subdivided recursively until a predefined refinement criteria is satisfied.
- Octants intersecting the surface are segmented into triangles.
- Local connectivity is extracted from the octree grid.



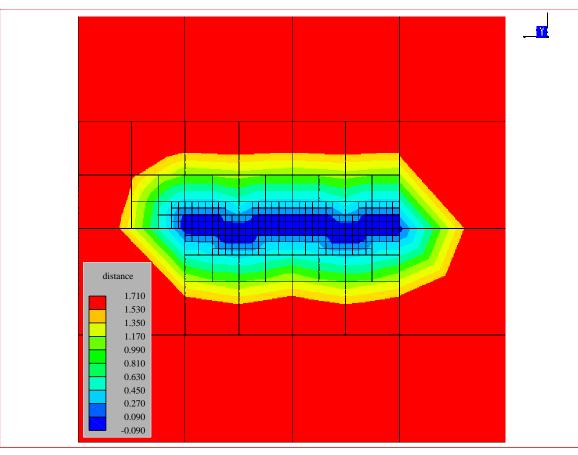
Level-Set Method for Surface Meshing of Complex Geometry





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Level-Set Method for Surface Meshing (cont'd)

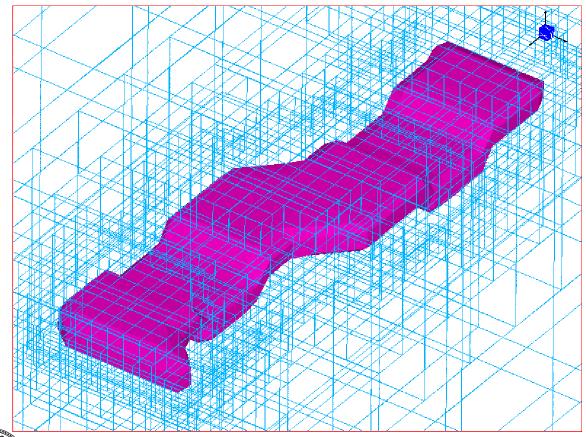


Mesh sectioning and distance contour for the word line



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Level-Set Method for Surface Meshing (cont'd)

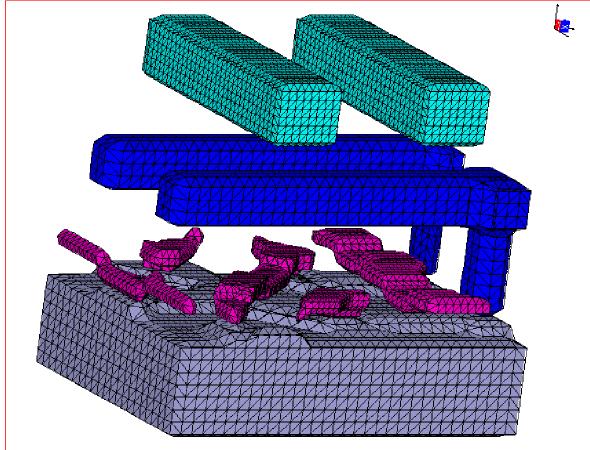


Iso-surface and octree for the word line



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Level-Set Method for Surface Meshing (cont'd)



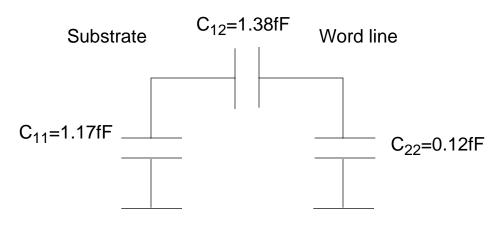
Mesh result for substrate, first poly layer and metal layers





Capacitance Extraction

- FASTCAP is used to analyze the realistic structures.
- The complete electrical model that FASTCAP provides for the word line vs. substrate:





Capacitance Extraction

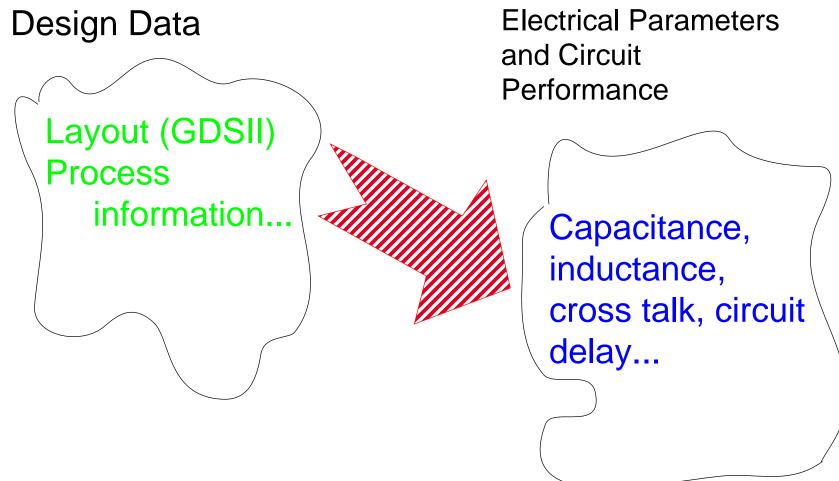
Capacitance among word line, bit lines and substrate:

	substrate	word line	bit line1	bit line2
substrate	2.92	1.27	0.36	0.36
word line		1.57	0.12	0.13
bit line1			1.01	0.27
bit line2				1.02

 Table 1: Capacitance Extraction Results (fF)



Realized Link from Geom. to Elec.





Conclusions

- A technology based interconnect modeling approach
- More realistic 3D geometry modeling which can be updated based on the design of layout and process specification
- More robust and efficient level-set meshing capabilities
- More accurate electrical parameter extraction based on realistic structures.



Related Work

- To model packaging parasitics (e.g. bonding wire's inductance) based on fast 3D geometry capturing (to be presented in IEDM '98, S.F.)
- To combine 3D solid modeling of package/ bonding-wire with compact model of RF power devices (BJT, LDMOS) to provide macro model for circuit simulation (SPICE, MDS)
- On-chip interconnect analysis including inductance and EMI.

